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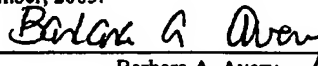
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named Inventor:	Bryan J. Root	
Appln. No.:	10/607,768	
Filed:	June 27, 2003	Examiner: Nguyen, Tung X.
Title:	Shielded Probe Apparatus for Probing Semiconductor Wafer	Group Art Unit: 2829

**AMENDMENT AND RESPONSE UNDER 37 C.F.R. 1.116**

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

I hereby certify that this document is being sent via First Class U. S. mail addressed to: Mail Stop AF, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on this 8th day of September, 2005.

  
Barbara A. Avery

Dear Sir:

In response to the Final Office Action of August 9, 2005 please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 5 of this paper.